

Successful Multi-Die System Design Using Synopsys 3DIC and Ansys Multiphysics Analysis



Kenneth Larsen

Director of Product
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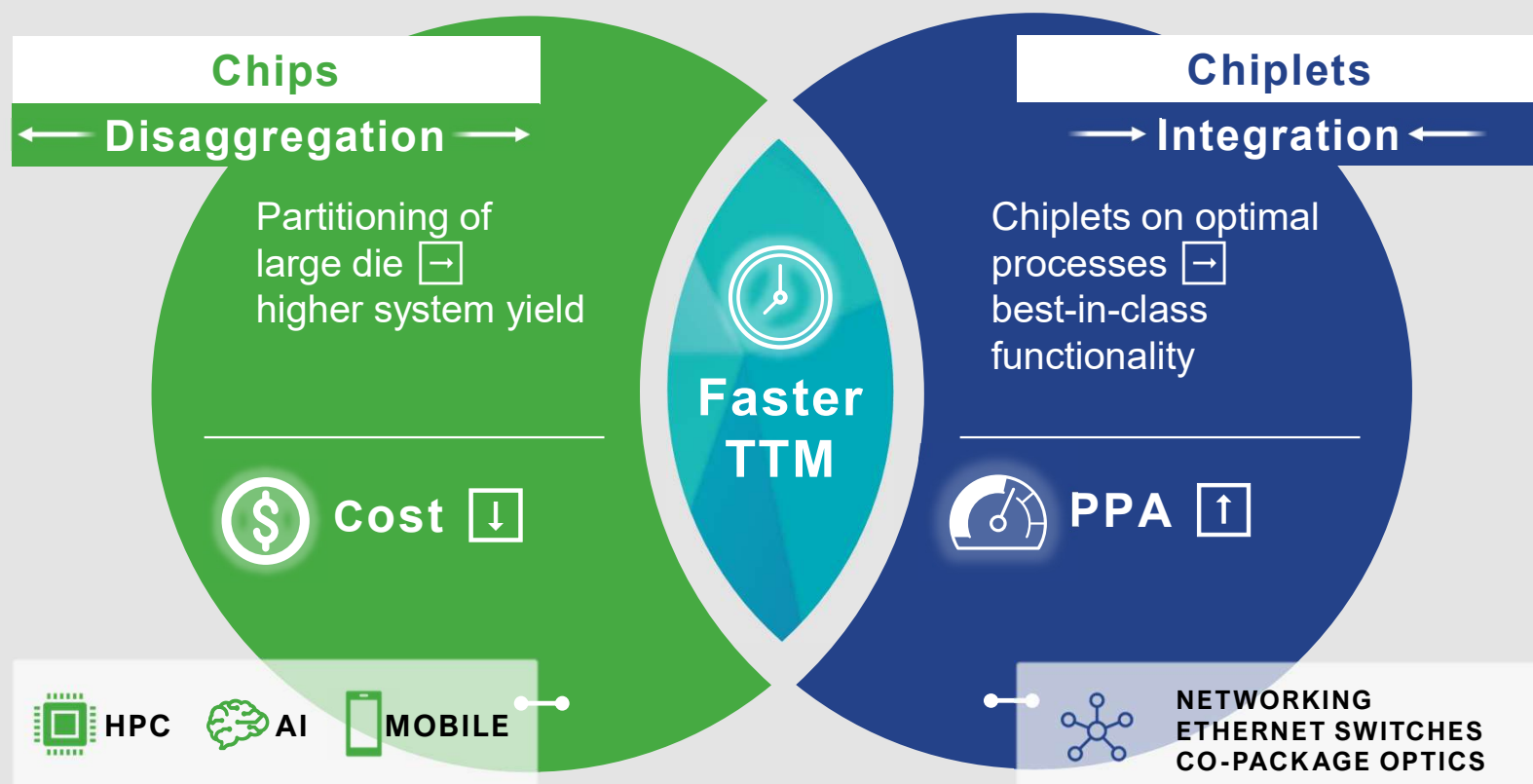
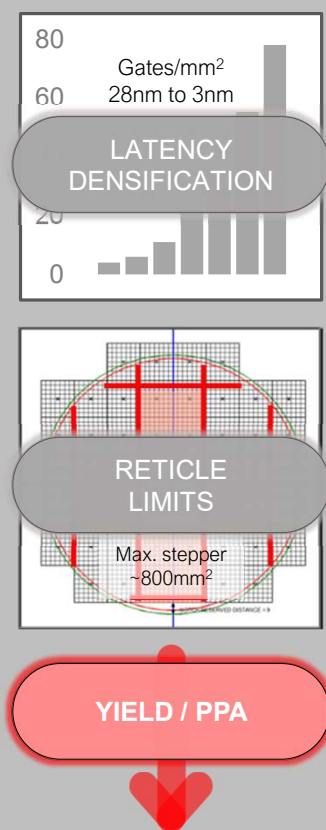


Marc Swinnen

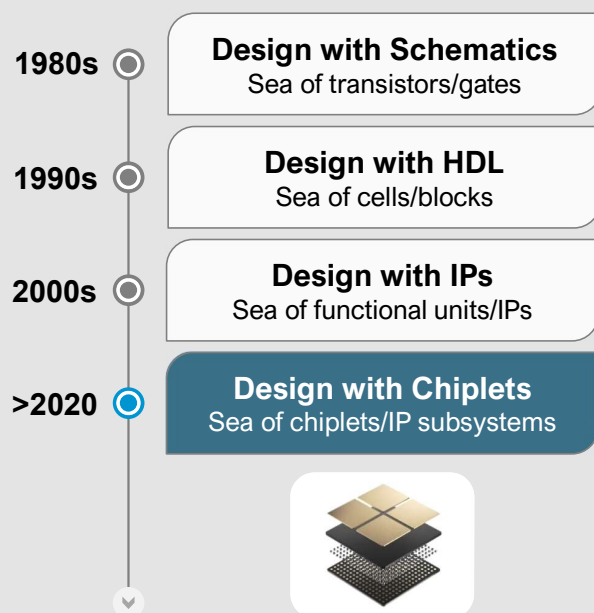
Director of Product
Marketing, Ansys

Market Drivers: The Demands for Data and Processing

Silicon Disruption from System-on-chip (SoC) to System-of-Chips...

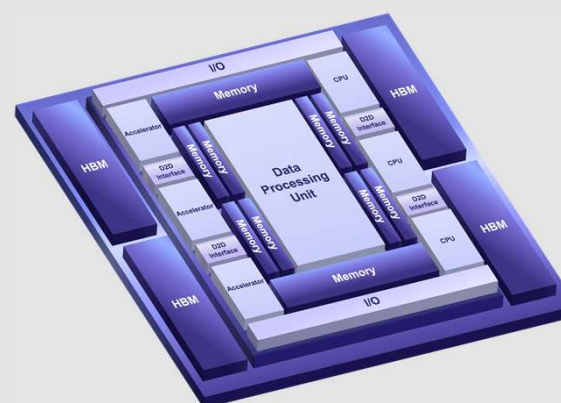


The Rise of Chiplet-Based Solutions



Source: "1000x More Compute for AI by 2025", Raja Koduri, Intel

System-of-Chiplets

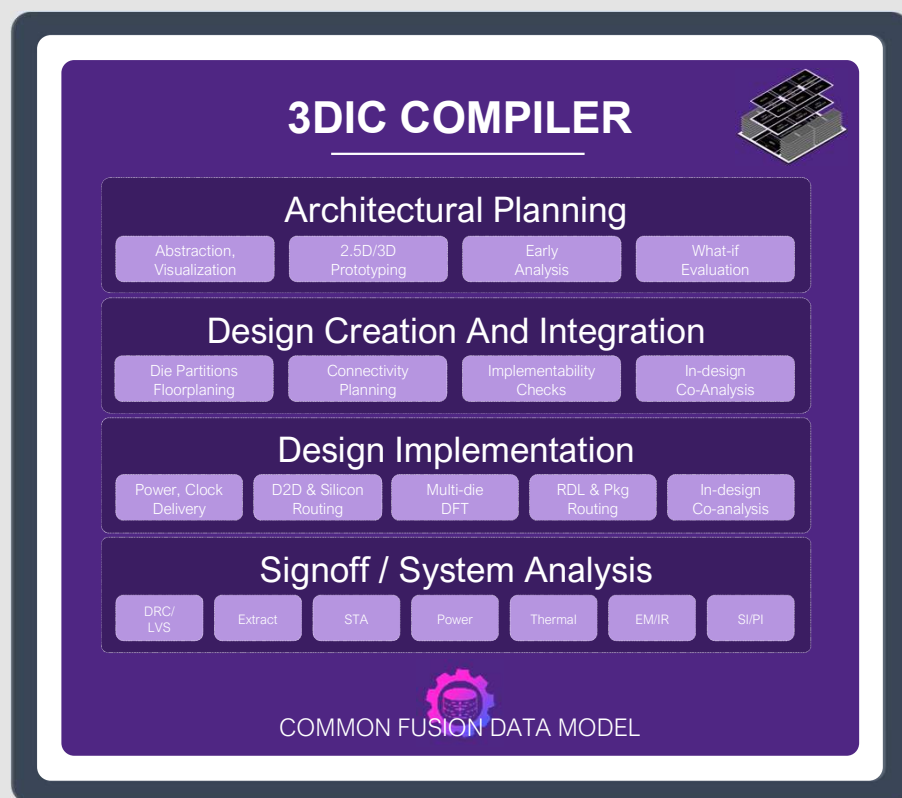


Benefits

- Better yield with smaller dies, exceeding reticle constraints
- Chiplets in its optimal technology, lower cost potential
- Reusability, targeting multiple markets
- Lower system power while increasing throughput

3DIC Compiler: The Unified Exploration-to-Signoff Platform

Extensible solution to accelerate 2.5D Chiplets, 3D Stack and Advanced Packages



Highly Integrated, Scalable Platform

Heterogeneous system-of-chips design and integration over **100s of Billions of transistors**



Flexible, Efficient Workflow Environment

Fast exploration and pathfinding to accelerate 3D design creation and D2D planning



Comprehensive Design and Closure

Full breadth of high-throughput engines – D2D/Pkg auto-routing, native DRC, DFT, ECO and more



Trusted, Golden Signoff Analysis

Integrated industry standard technologies (**Synopsys** + **Ansys**) for convergence to optimal PPA/mm³ (incl. Thermal, EM/IR, SI/PI, STA)

3D Solutions Certified by TSMC for 3DFabric™ SoIC™, CoWoS™, and InFO™



Synopsys Expands Strategic Technology Collaboration with TSMC to Extend 3D-System Integration Solutions for Next-Generation High-Performance Computing Designs

Synopsys' 3DIC Compiler Delivers Seamless Access to TSMC 3DFabric Technologies



MOUNTAIN VIEW, Calif., Oct. 20, 2021 /PRNewswire/ --

Highlights of this Announcement:

- Expanded strategic collaboration delivers comprehensive 3D-system integration capabilities, enabling the aggregation of hundreds of billions of transistors in a single package
- Synopsys 3DIC Compiler, the unified, multi-die implementation platform, seamlessly integrates TSMC 3DFabric technologies-based design methodologies, to offer a complete exploration-to-signoff design platform
- This joint collaboration combines TSMC's technology advancements with the converged architecture, advanced in-design analysis framework and signoff tools of 3DIC Compiler to deliver the required



Ansys Multiphysics Solutions Certified by TSMC for High-Speed Next-Generation 3D-IC Packaging Technologies

TSMC leverages Ansys' multiphysics platform to analyze power, thermal and signal integrity for its CoWoS® and InFO technologies

Key Highlights

- Ansys achieved certification of its advanced semiconductor design solution for TSMC's high-speed CoWoS® (Chip-on-Wafer-on-Substrate) and InFO (Integrated Fan-Out) 2.5D and 3D advanced packaging technologies
- Ansys' comprehensive suite of power, thermal and signal integrity analysis engines simulate, calculate and alleviate reliability issues, enabling optimal electrical performance



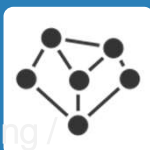
3DIC Compiler Platform Technology Highlights

Fast, Analysis-Driven
“What-if” Exploration

Design Realization and Validation

Pathfinding-to-Closure Cockpit

System Creation



Multi-Die Multi-Tech Prototyping /
Floor-planning / Integration

Die partitioning

What-if Analysis

Auto Bump/TSV Management

Design Implementation



Fast, Auto / Assisted Routing

Full-Stack Bumps/TSV Creation

Multi-die DRC and LVS

Multi-Die Test Access and DFT
Support

System Analysis



Complete Analysis Solution

- Full-spectrum, multi-physics analysis – electrical, thermal, signal and power integrity

Early-Design Analysis
Support

- Fast, In-design-level accuracy

3D Data Management Environment

COMMON FUSION 3D DESIGN DATA MODEL

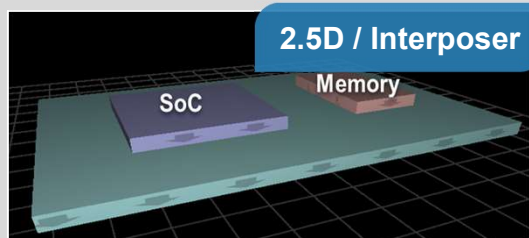


System Exploration And Creation

Iteratively Explore, Create, Optimize in One Place

Intuitive UI for Ease-of-Use and Productivity for 2.5D/3D Design

Architecture

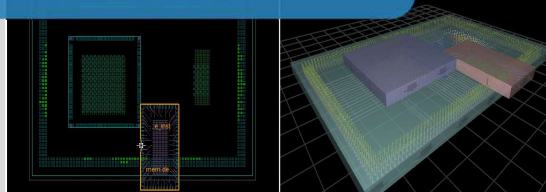


3D Stacked Die

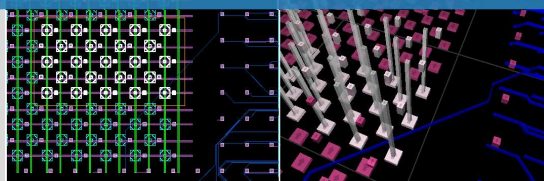


Creation

Interactive Die Placement

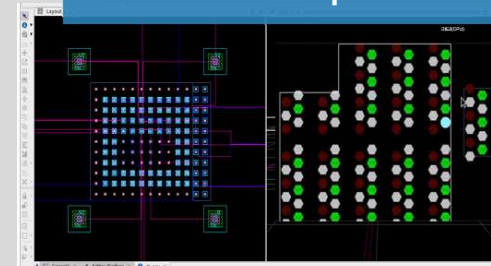


C4 and TSV Selection for Modification

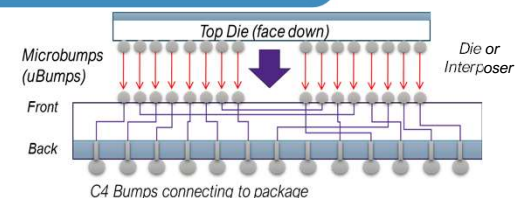


Analysis Driven Optimization

Interactive Bump Creation

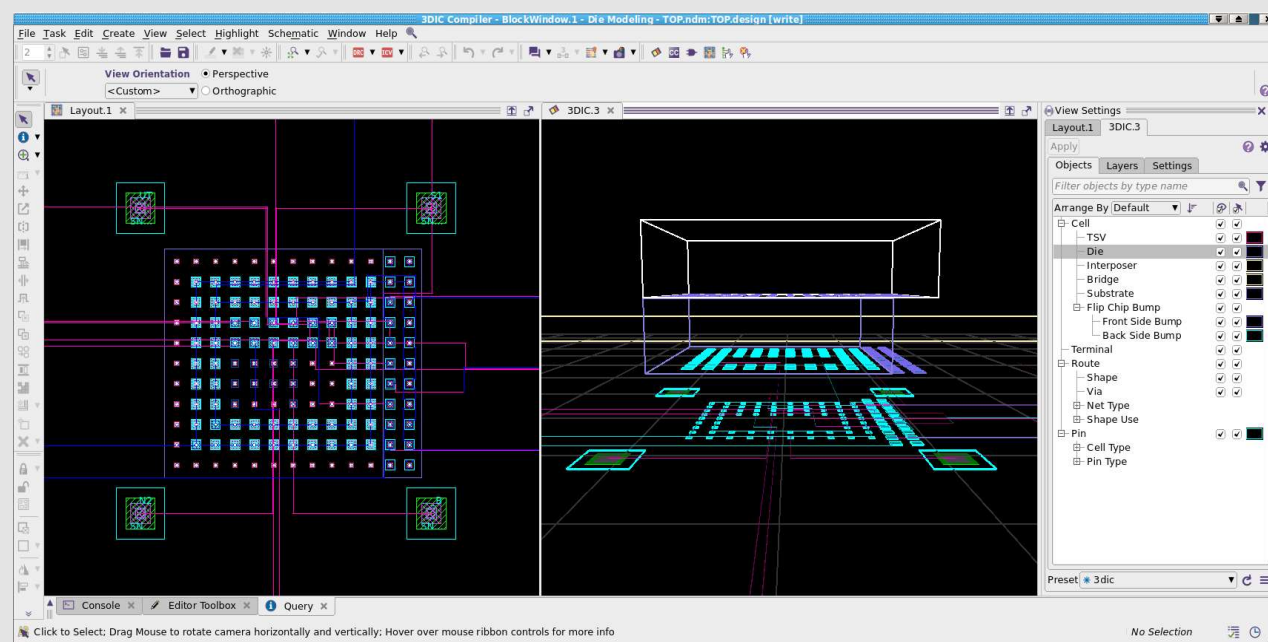
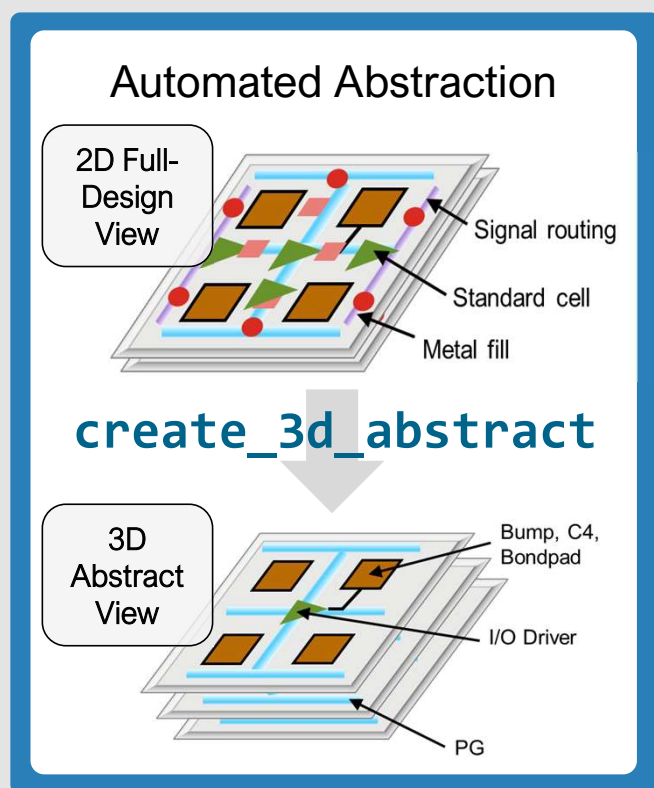


Auto Bump Mirroring



Automated Abstraction Enables Fast Exploration

Single data model delivers fast and seamless data and context management

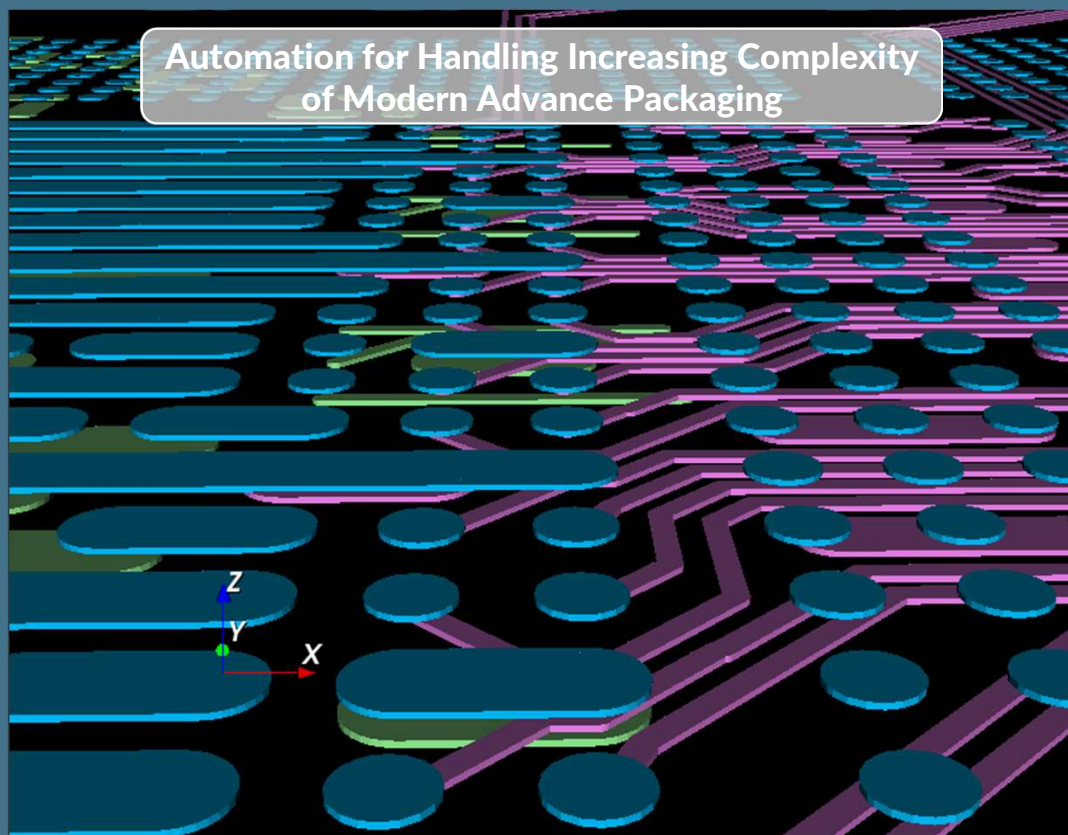


Work with the appropriate level of design details
merge_abstract to go back to full-design view

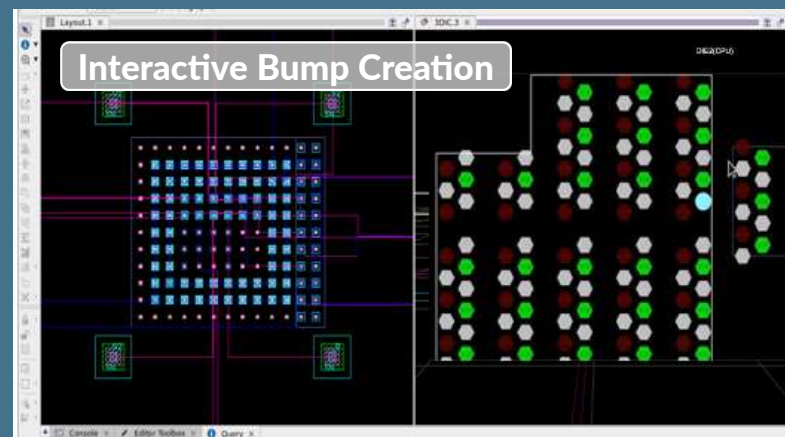
Meeting The Full-stack Scalability Challenge

3DIC Compiler Bump Management

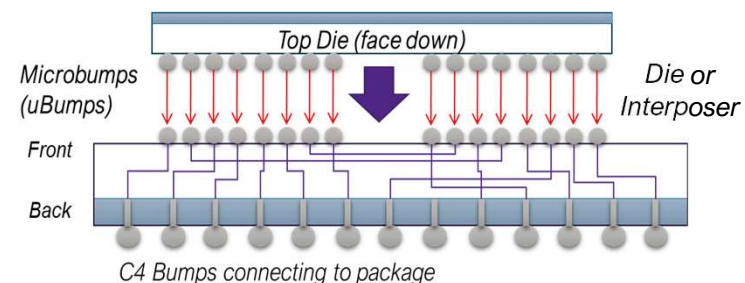
Automation for Handling Increasing Complexity of Modern Advance Packaging



Interactive Bump Creation



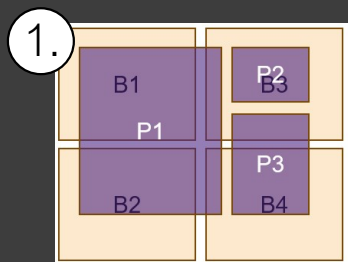
Automatic Bump Mirroring



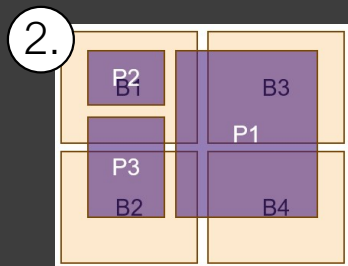
Exploring Alternatives For Power Delivery

Thermal Analysis Example: Floorplanning Trade-offs

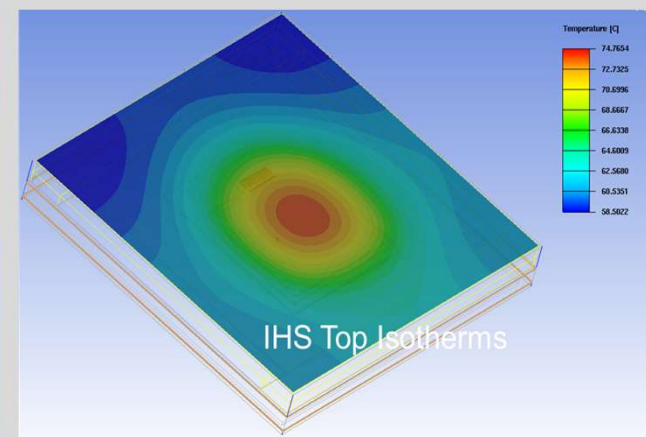
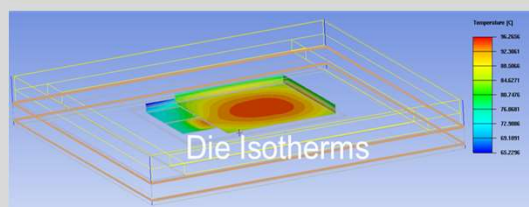
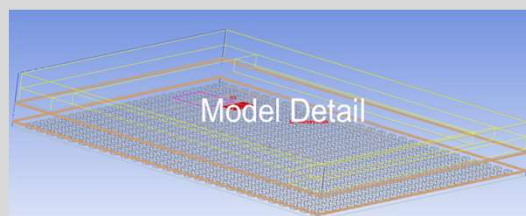
Exploring Floorplan Efficacy



VS.



Multi-Die-Package Thermal Maps



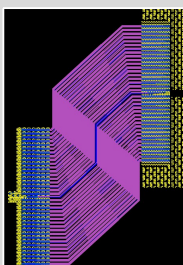
$$\text{Theta-JC} = (96.27 - 74.77) / 36 = 0.597 \text{ } ^\circ\text{C/W}$$

Design Implementation

The background of the slide is an aerial photograph of a city at night. The left side of the image is covered by a semi-transparent purple circular overlay. The right side of the image shows a city street with buildings and lights, highlighted in a yellowish-orange glow.

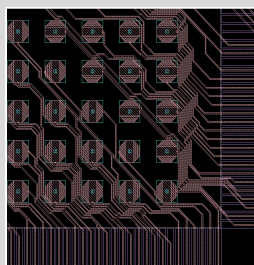
Fast, Automated Routing Technologies for All Architectures

Auto-HBM Routing



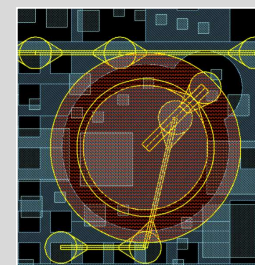
JEDEC HBM bus routing support with optional shielding and differential pairs

RDL Routing



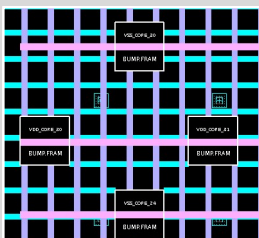
Net-based 45-degree RDL (Redistribution Layer) Routing

Custom Routing



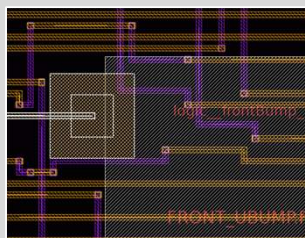
Visually-assisted automated custom layout editing for productivity

PG Routing



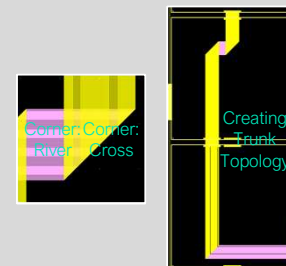
PG grids, rails and straps synthesis with specified pitch

Signal Routing



Net-based 90-degree full-chip signal routing with high-perf DRC, optimization & congestion management

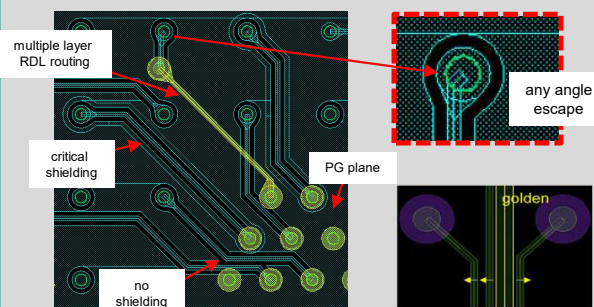
Bus/Trunk Routing



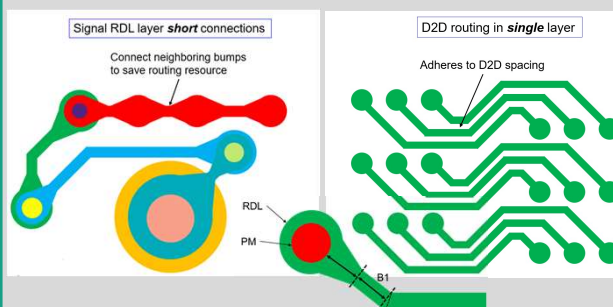
Easy-to-use and fast innovative bus routing

Unique Automated Solution for Advanced Packaging

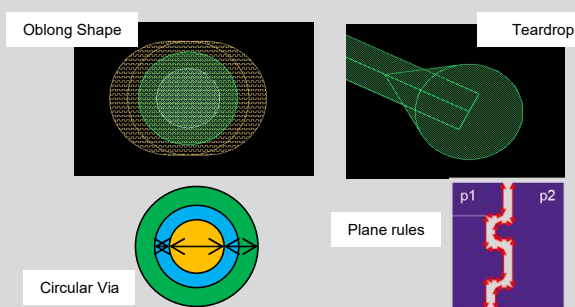
RDL And Push-Aside Routing



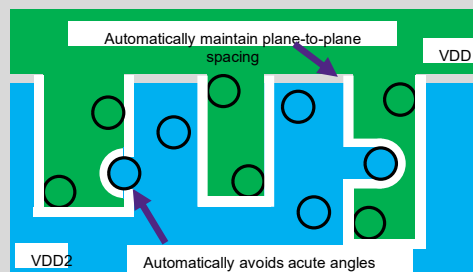
RDL Substrate Auto-Routing



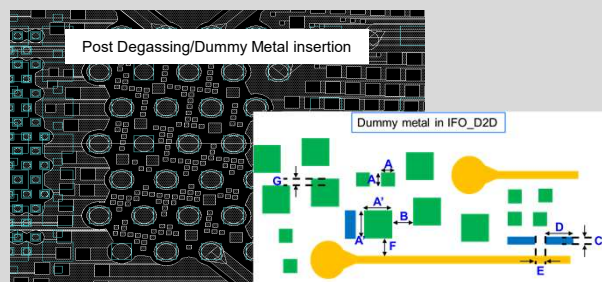
Specific Shapes



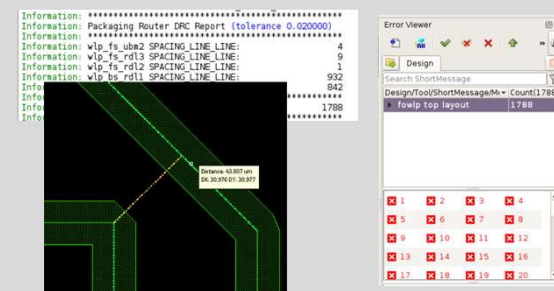
DRC-Aware P/G Realization



Degassing / Metal fill



Package DRC



Native 3D Multi-Die And Package DRC

Inter-die Alignment

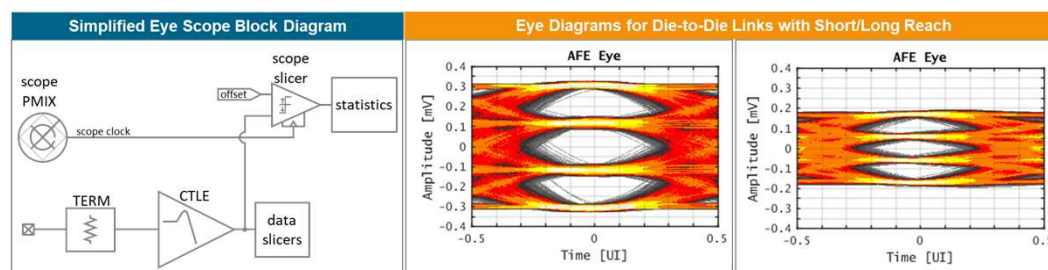
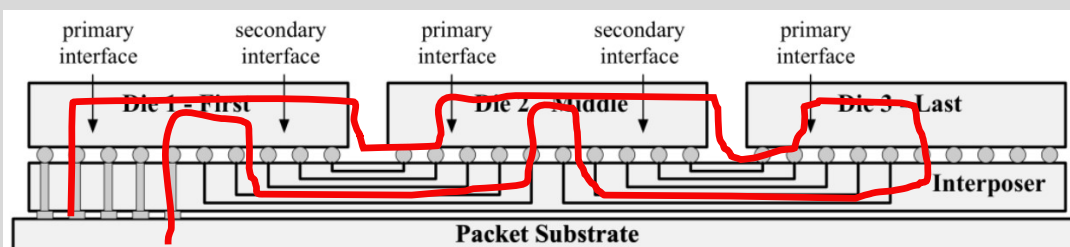
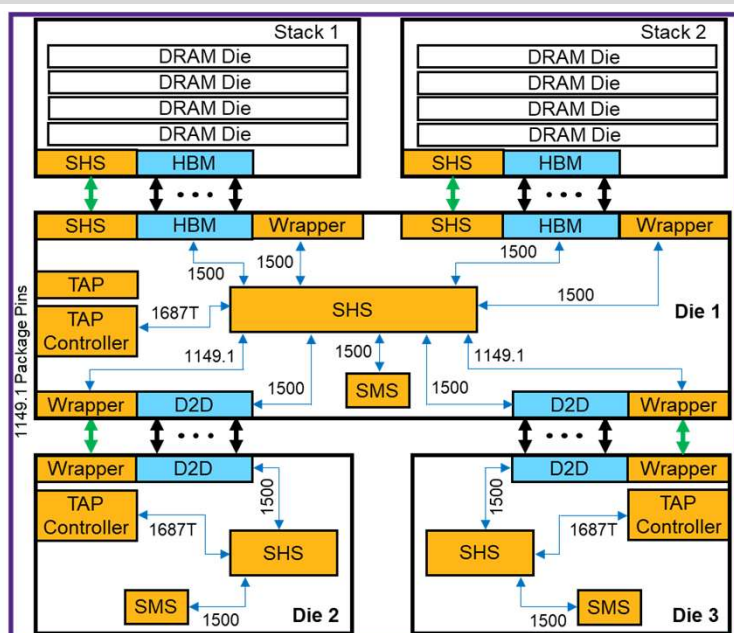
Inter-die Connectivity

Chip Placement

3D Visualization of Design Checks

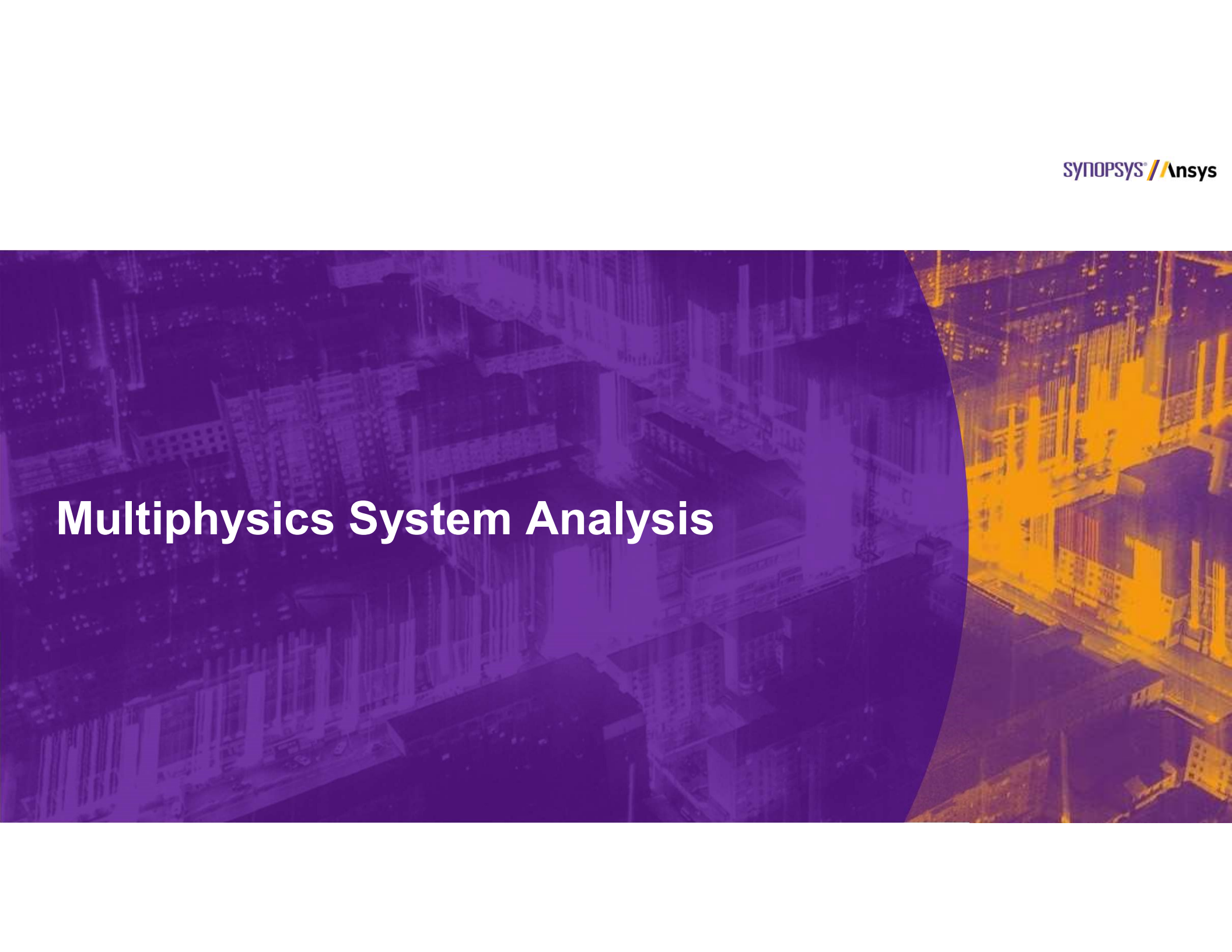
Integrated Test Access and Connectivity Validation

IEEE1838 Test Access Architecture for 3DIC

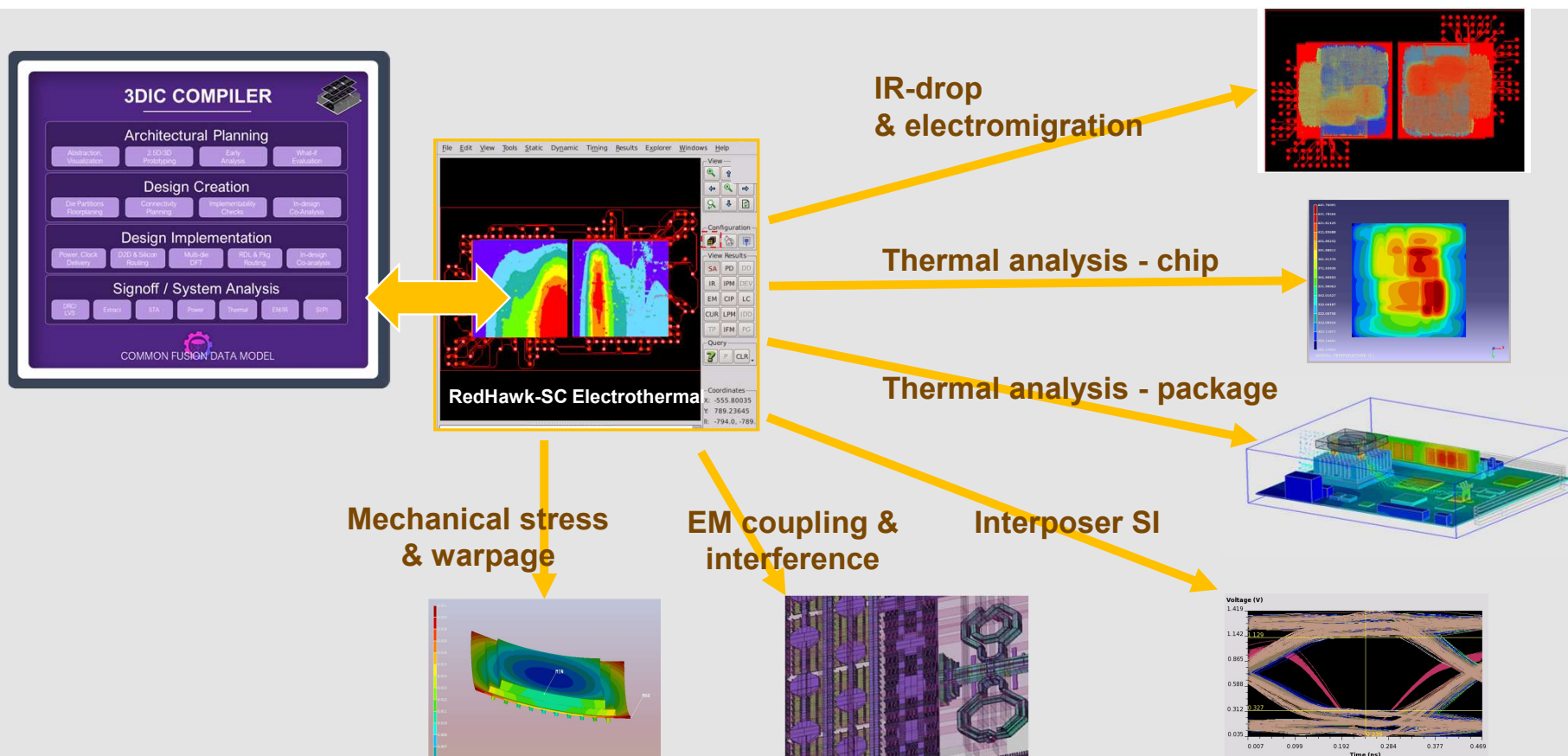


Internal Eye Scope Enables Validation of Die-to-Die Link Quality

Multiphysics System Analysis

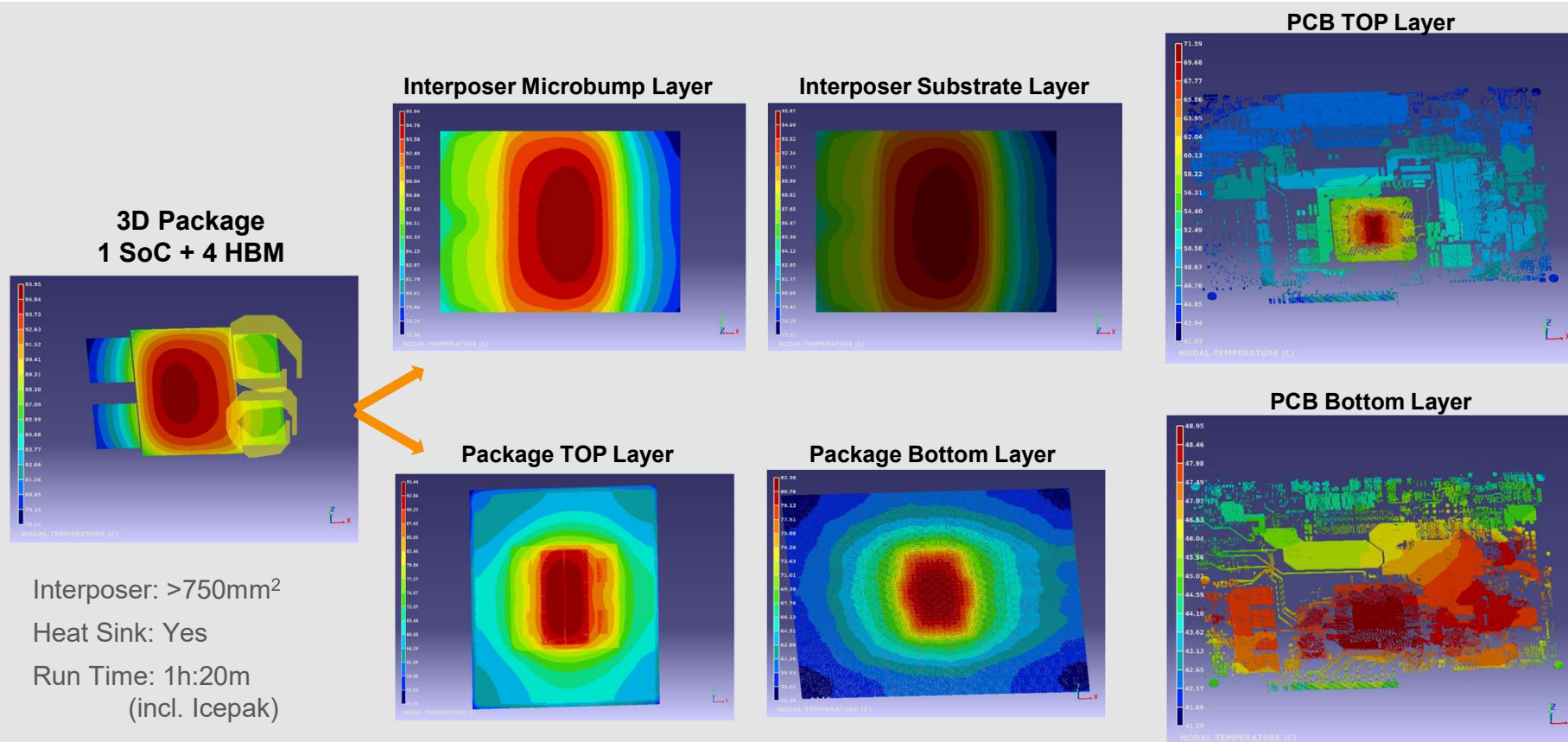
The background of the slide is an aerial photograph of a city at night. The left side of the image is covered by a semi-transparent purple circular overlay, while the right side is covered by a semi-transparent yellow/orange circular overlay. The city lights are visible through these overlays.

Integrated Chip-Package Multiphysics Co-simulation



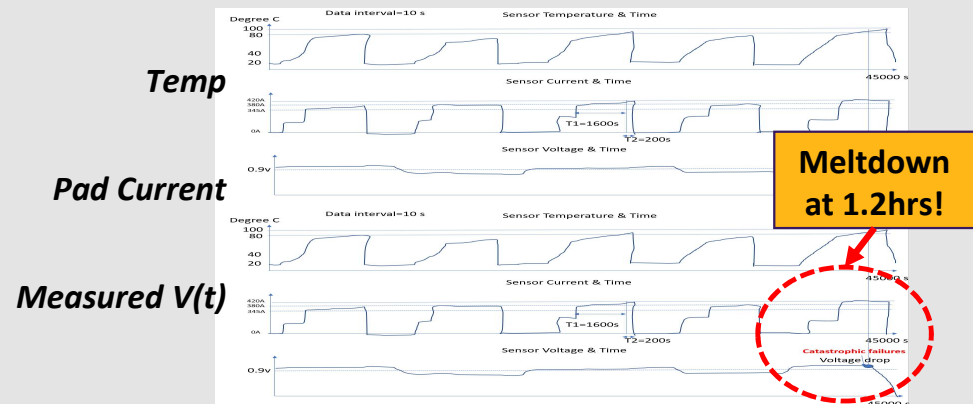
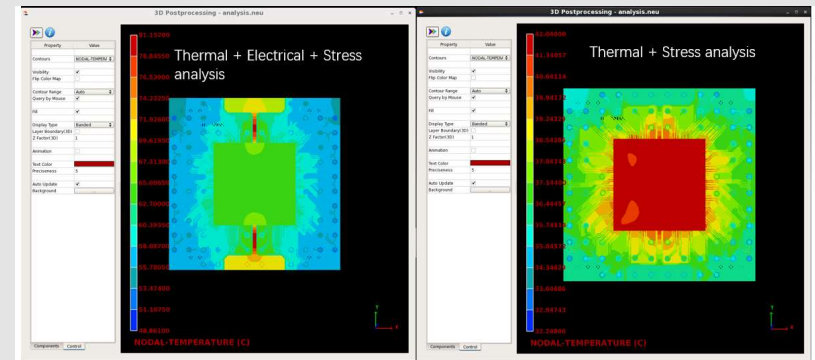
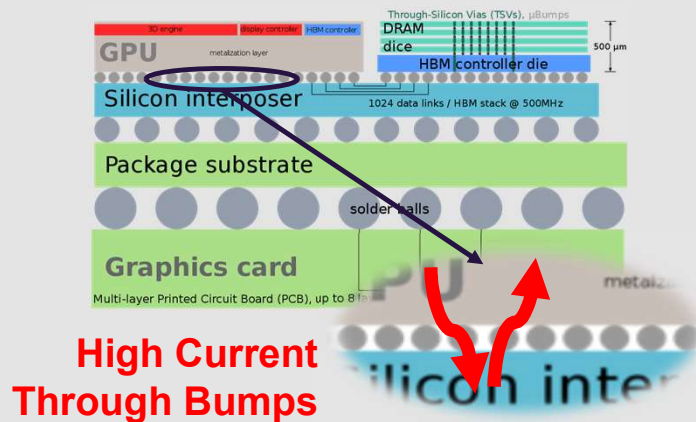
RedHawk-SC Electrothermal Thermal Analysis

Full Stack 3DIC Detailed Temperature Profile Maps



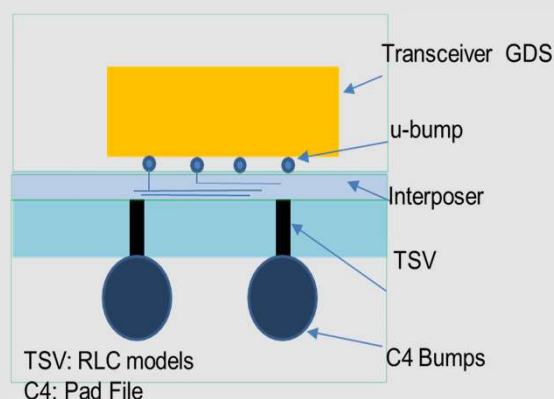
Case Study: RedHawk-SC Electrothermal Catches Meltdown Issue

- High-power HPC design
- Electro-thermal issue on micro-bumps.
- RedHawk-SC Electrothermal catches this by simulating Joule heating effects and applying pad currents from RedHawk-SC



3DIC Chip Level Concurrent EMIR Analysis

Prevent overdesign/underdesign by concurrently analyzing the chip and interposer for accurate current distribution



Design Specification:

- . High-speed Transceivers in 16nm FinFET FPGA
- . 120x32.75Gb/s SerDes
- . 2.58M Programmable Logic Cells w/ DSPs
- . 3 fabric slices on CoWoS, 20B Transistors

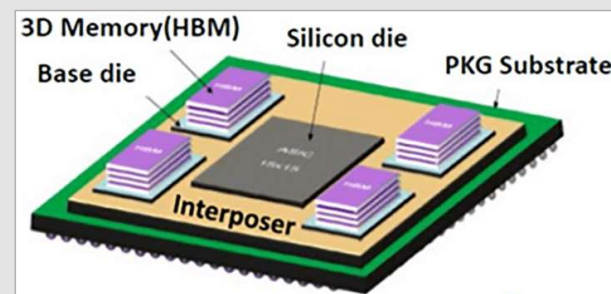
Analysis Type between Chip and Interposer		
Separate Analysis	Concurrent Analysis	
PAD Current	PAD Current	Eliminate False EM violation
IR Map	IR Map	Found Hidden IR Drop weak area

Ling Yang, "Concurrent 3DIC Power Supply Analysis for Xilinx Serdes Interface", DesignCon 2018

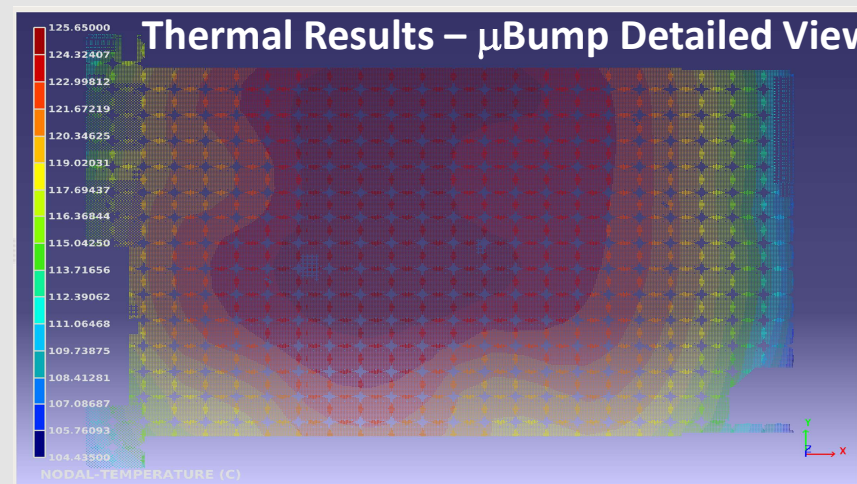
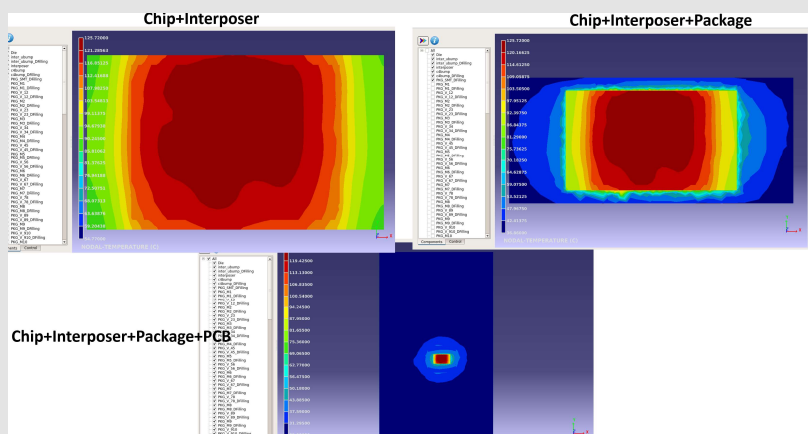
Detailed Temperature Profiles for CoWoS® Down to Each mBump

AI/Networking Chip Company

Silicon Die + Interposer + 4 HBM
Connector Bumps: 100k+
3D-IC Package: 10+ metal layer CoWoS®
Board: 20 metal layer, ~70,000mm²
Peak Memory Usage: 473GB
Full Thermal Analysis Run Time: ~40Hrs



Thermal Results Overview



Summary

- **3DIC Compiler provides industry's only unified platform** for exploration-to-design-and-signoff of 2.5D/3D multi-die/chiplets advanced package systems
- **Integration with Ansys' multi-physics suite of products** delivers golden analysis for entire system – includes EM/IR, thermal, electromagnetic, mechanical
- **Co-design and analysis accelerates** exploration, planning and implementation to achieve fast **design convergence and optimal PPA/mm³**

THANK YOU





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